

### EPS13D2 C 1 H A -27.000M

Series —
RoHS Compliant (Pb-free) 3.3V 4 Pad 5mm x 7mm
Ceramic SMD LVCMOS Programmable Spread
Spectrum Oscillator

y Cycle —

Nominal Frequency 27.000MHz Spread Spectrum

±0.25% Center Spread

Output Control Function

Tri-State

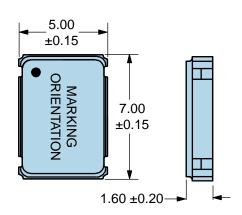
Duty Cycle 50 ±10%

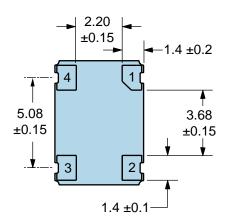
ELECTRICAL SPECIFICAT	ELECTRICAL SPECIFICATIONS		
Nominal Frequency	27.000MHz		
Frequency Stability	±100ppm Maximum over Operating Temperature of -20°C to +70°C (Inclusive of all conditions: Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at 25°C, Shock, and Vibration.)		
Aging at 25°C	±5ppm First Year Maximum		
Supply Voltage	3.3Vdc ±0.3Vdc		
Maximum Supply Voltage	-0.5Vdc to +7.0Vdc		
Input Current	30mA Maximum (Unloaded; Vdd=3.3Vdc)		
Output Voltage Logic High (Voh)	Vdd-0.4Vdc Minimum (IOH=-8mA)		
Output Voltage Logic Low (Vol)	0.4Vdc Maximum (IOL=+8mA)		
Rise/Fall Time	2.7nSec Maximum (Measured at 20% to 80% of Waveform)		
Duty Cycle	50 ±10% (Measured at 50% of Waveform)		
Load Drive Capability	15pF Maximum		
Output Logic Type	CMOS		
Output Control Function	Tri-State (High Impedance Internal Pull Down Resistor of 100kOhms Typical on Pad 3, Internal Pull Up Resistor of 100kOhms Typical on Pad 1)		
Tri-State Input Voltage (Vih and Vil)	70% of Vdd Minimum or No Connection to Enable Output, 30% of Vdd Maximum to Disable Output		
Tri-State Output Disable Time	350nSec Maximum		
Tri-State Output Enable Time	350nSec Maximum		
Disable Current	20mA Maximum (Unloaded; Pad 1=Ground; Vdd=3.3Vdc)		
Spread Spectrum	±0.25% Center Spread		
Modulation Frequency	30kHz Minimum, 31.5kHz Typical, 33kHz Maximum		
Period Jitter	400pSec Maximum (Cycle to Cycle; Spread Spectrum-On; Vdd=3.3Vdc)		
Start Up Time	10mSec Maximum		
Storage Temperature Range	-55°C to +125°C		

ENVIRONMENTAL & MECHANICAL SPECIFICATIONS		
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	
Mechanical Shock	MIL-STD-202, Method 213, Condition C	
Resistance to Soldering Heat	MIL-STD-202, Method 210	
Resistance to Solvents	MIL-STD-202, Method 215	
Solderability	MIL-STD-883, Method 2003	
Temperature Cycling	MIL-STD-883, Method 1010	
Vibration	MIL-STD-883, Method 2007, Condition A	



### **MECHANICAL DIMENSIONS (all dimensions in millimeters)**



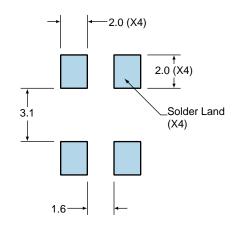


PIN	CONNECTION
1	Tri-State
2	Case/Ground
3	Output
4	Supply Voltage

LINE	MARKING
1	ECLIPTEK
2	27.000M
3	SXXYZZ S=Configuration Designator XX=Ecliptek Manufacturing Code Y=Last Digit of the Year ZZ=Week of the Year

#### **Suggested Solder Pad Layout**

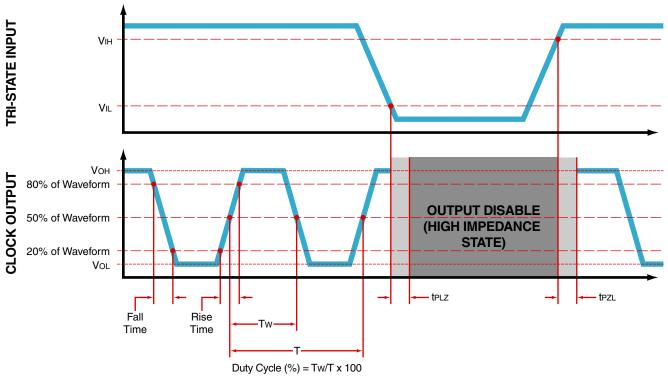
All Dimensions in Millimeters



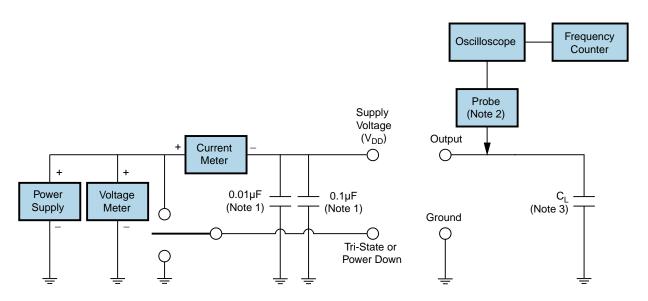
All Tolerances are ±0.1



#### **OUTPUT WAVEFORM & TIMING DIAGRAM**



#### **Test Circuit for CMOS Output**



- Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V<sub>DD</sub> pin is required.
- Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.
- Note 3: Capacitance value  $\dot{C}_L$  includes sum of all probe and fixture capacitance.



## **Recommended Solder Reflow Methods**



### **High Temperature Infrared/Convection**

T <sub>s</sub> MAX to T <sub>∟</sub> (Ramp-up Rate)	3°C/second Maximum
Preheat	
- Temperature Minimum (Ts MIN)	150°C
- Temperature Typical (T <sub>s</sub> TYP)	175°C
- Temperature Maximum (T <sub>s</sub> MAX)	200°C
- Time (t <sub>s</sub> MIN)	60 - 180 Seconds
Ramp-up Rate (T <sub>L</sub> to T <sub>P</sub> )	3°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	217°C
- Time (t∟)	60 - 150 Seconds
Peak Temperature (T <sub>P</sub> )	260°C Maximum for 10 Seconds Maximum
Target Peak Temperature (T <sub>P</sub> Target)	250°C +0/-5°C
Time within 5°C of actual peak (tp)	20 - 40 seconds
Ramp-down Rate	6°C/second Maximum
Time 25°C to Peak Temperature (t)	8 minutes Maximum
Moisture Sensitivity Level	Level 1



### **Recommended Solder Reflow Methods**



#### Low Temperature Infrared/Convection 240°C

T <sub>S</sub> MAX to T <sub>L</sub> (Ramp-up Rate)	5°C/second Maximum
Preheat	
- Temperature Minimum (T <sub>s</sub> MIN)	N/A
- Temperature Typical (T <sub>s</sub> TYP)	150°C
- Temperature Maximum (T <sub>s</sub> MAX)	N/A
- Time (t <sub>s</sub> MIN)	60 - 120 Seconds
Ramp-up Rate (T <sub>L</sub> to T <sub>P</sub> )	5°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	150°C
- Time (t∟)	200 Seconds Maximum
Peak Temperature (T <sub>P</sub> )	240°C Maximum
Target Peak Temperature (T <sub>P</sub> Target)	240°C Maximum 1 Time / 230°C Maximum 2 Times
Time within 5°C of actual peak (t <sub>p</sub> )	10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time
Ramp-down Rate	5°C/second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1

#### **Low Temperature Manual Soldering**

185°C Maximum for 10 seconds Maximum, 2 times Maximum.

#### **High Temperature Manual Soldering**

260°C Maximum for 5 seconds Maximum, 2 times Maximum.